Amendment to the Claims

A complete list of all the presently or formerly pending claims in the application is provided below, with suitable headings to show the status of each claim.

1. (Currently Amended) An X-ray tube subsystem comprising:

an X-ray tube including a grid connected to a grid bias connection, a cathode connected to a filament bias connection, an anode connected to an anode bias connection; and

a variable grid voltage supply connected between the grid bias connection and the filament bias connection, said grid voltage supply producing a positive ion collection voltage on the order of 10 to 30 volts to produce a negative output voltage level at the grid bias connection with respect to the filament bias connection, the output voltage level of the variable voltage supply adapted to produce a first voltage level to focus an electron beam, a second voltage level to collect ions, and a third voltage level to stop the electron beam.

2. (Cancelled)

- 3. (Currently Amended) The X-ray tube subsystem of claim 1, wherein a magnitude of the second voltage level is greater than 100-volts, and a magnitude of the first voltage level is in a range of 10 to 30 volts said grid is adapted to receive a focus voltage, a stop voltage and said ion collection voltage.
- 4. (Previously presented) The X-ray tube subsystem of claim 1, further comprising a Faraday cage surrounding the variable voltage supply.
 - 5. (Cancelled)
- 6. (Original) The X-ray tube subsystem of claim 1, further comprising a filament voltage supply connected to the filament bias connection.
- 7. (Previously presented) The X-ray tube subsystem of claim 6, wherein a Faraday cage is connected to the filament voltage supply.

- 8. (Previously presented) The X-ray tube subsystem of claim 6, further comprising an anode voltage supply connected to the anode bias connection and a ground reference, and a cathode voltage supply connected to an earth ground and the filament bias connection.
- 9. (Currently Amended) A method for operating an X-ray system to reduce high voltage breakdown events, the method comprising:

providing an X-ray tube that includes a grid connected to a grid bias connection and a cathode connected to a filament bias connection; and

during X-ray tube operation, varying a voltage level between the grid bias connection and the filament bias connection to produce a first voltage level to focus an electron beam, a second voltage level to collect ions, and a third voltage level to stop the electron beam creating an ion collection voltage between the grid bias connection and the filament connection on the order of 10 to 30 volts.

- 10. (Cancelled)
- 11. (Cancelled)
- 12. (Currently amended) The method of claim 9, further comprising providing a Faraday cage surrounding a variable voltage supply that generate the first-voltage level, the second voltage level, and the third voltage level grid voltage supply that creates the ion collection voltage.
- 13. (Original) The method of claim 12, further comprising providing a connection between the Faraday cage and the filament bias connection.

14. (Currently Amended) An X-ray examination system comprising:

an X-ray tube including a grid connected to a grid bias connection and a cathode connected to a filament bias connection;

a variable voltage supply connected between the grid bias connection and the filament bias connection, said grid voltage supply producing a positive ion collection voltage on the order of 10 to 30 volts to sweep free ions out of the x-ray tube to produce a negative output voltage level at the grid bias connection with respect to the filament bias connection, the output voltage level of the variable voltage supply adapted to produce a first voltage level to focus an electron beam, a second voltage level to sweep free ions out of the X-ray tube, and a third voltage level to stop the electron beam;

an X-ray detector to receive an X-ray beam; and

readout electronics connected to the X-ray detector.

15. (Cancelled)

- 16. (Currently Amended) The X-ray examination of claim 14, further comprising a Faraday cage surrounding the variable voltage supply.
- 17. (Original) The X-ray examination system of claim 16, wherein the Faraday cage is connected to the filament bias connection.

18. (Cancelled)

19. (Original) The X-ray examination system of claim 14, wherein the free ions are positive ions generated in proximity to an X-ray tube cathode during operation of the X-ray examination system.

20. (Cancelled)

- 21. (Currently amended) The X-ray tube subsystem of claim 1, wherein said X-ray tube forms positive ions about said cathode, and said-second voltage level at said grid-is negative with respect to said filament bias connection to cause said positive ions to be collected at said grid and said grid voltage supply is a variable grid voltage supply.
- 22. (Currently amended) The method of claim 9 wherein said X-ray tube produces positive ions about said cathode, and said ion collection voltage is created through a variable voltage supply.
- 23. (Currently amended) The X-ray examination system of claim 14 wherein said X-ray tube forms positive ions about said cathode, and said second-voltage level at said grid is negative with respect to said filament bias connection to cause said-positive ions to be collected at said grid and said grid voltage supply is a variable grid voltage supply.
- 24. (Previously presented) The X-ray tube subsystem of claim 1 wherein said X-ray tube produces ions and said grid collects said ions at said grid to eliminate effects of said ions on an electric field around said cathode.
- 25. (Previously presented) The method of claim 9 wherein said X-ray tube produces ions and said grid collects said ions at said grid to eliminate effects of said ions on an electric field around said cathode.
- 26. (Previously presented) The X-ray examination system of claim 14 wherein said X-ray tube produces ions and said grid collects said ions at said grid to eliminate effects of said ions on an electric field around said cathode.